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INSTRUMENTATION AND MEASUREMENT SOCIETY NEWSLETTER

September 2014

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Editor-in-Chief Message



["Achieving Excellence Through Quality"](#)

by Alessandro Ferrero

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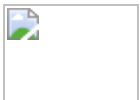
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IEEE Instrumentation & Measurement Magazine

The August Issue of [IEEE Instrumentation & Measurement Magazine](#) is in the mail and is

About the IEEE Instrumentation and Measurement Society Newsletter

Engineers today start their careers with excellent technical skills and subject matter. The IEEE Instrumentation and Measurement Society (I&M) Newsletter includes time sensitive news useful to its members and highlights content of the current issue of *IEEE Instrumentation and Measurement Magazine*.

I&M Conference Calendar



IEEE AUTOTEST 2014 will be held 15-18 September 2014 in St. Louis, Missouri, USA.

IEEE AUTOTEST 2014 is pleased to offer Department of Defense civilian and active-duty military attendees complimentary registration to the technical program and product display and demonstration areas.

Visit the conference [Web site](#) for more information.



The 2014 International IEEE Symposium on Precision Clock Synchronization for Measurement, Control and Communication (ISPCS 2014) will be held 21-26 September 2014 in Austin, Texas, USA.

Visit the conference [Web site](#) for more information.



The 2014 IEEE International Workshop on Applied Measurement for Power Systems (AMPS) will be held 24-26 September 2014, in Aachen, Germany.

Visit the conference [Web site](#) for more information.



retrievable now from IEEE *Xplore*, the IEEE online digital library.

All *IEEE Instrumentation & Measurement Magazine* subscribers can access the online edition using their [IEEE Account](#).

 [Image of Aug 2014 IEEE I&M Magazine](#)

Feature articles in this issue:

- "Versatile 20 GHz wideband RF digitizer for test and measurement"
- "RF recording techniques to resolve wireless channel interference problems"
- "LXI in satellite system testing"
- "Considerations in the design of a boundary scan runtime library"
- "Reconfigurable real-time hardware-in-the-loop environment for automotive electronic control unit testing and verification"
- "Stop that interference! [Basic Metrology]"
- "The mathematical theory of evidence and measurement uncertainty"
- "The smartphone-enabled DMM"

I&M Chapters

On the I&M Chapter Activities [Web site](#), you can find resources to help in Chapter formation, Chapter Activities, Chapter funding, etc.

Please contact [Sergio Rapuano](#), I&M Chapter Liaison, with any questions or concerns.

IEEE Senior Membership

IEEE Senior Membership is the highest grade for which application may be made and requires experience reflecting professional maturity. Candidates need to be an engineer, scientist, educator, technical executive, or originator in IEEE-designated fields in

The 2014 IEEE International Symposium on Haptic Audio-Visual Environments and Games (HAVE 2014) will be held 10-11 October 2014, in Dallas, Texas, USA.

Visit the conference [Web site](#) for more information.



The 2014 IEEE International Symposium on RObotic and SEnsors Environments (ROSE 2014) will be held 16-18 October 2014, in Timisoara, Romania.

Visit the conference [Web site](#) for more information.



The 2015 IEEE International Instrumentation and Measurement Technology Conference (I2MTC) will be held 11-14 May 2015 in Pisa, Italy.

Important Deadlines:

- Submission of FULL PAPERS: 15 September 2014
- Notification of Acceptance, Rejection, or Revision: 5 December 2014
- Submission of Final Paper: 12 January 2015
- Final Paper Acceptance: 9 February 2015

View the [authors instructions](#) for papers.

View the I2MTC 2015 [Call for Papers](#).

Visit the conference [Web site](#) for more information.

Distinguished Lecturer Program

The I&M Society Distinguished Lecturer Program (DLP) provides I&M Chapters around the world with talks by experts on topics of interest and importance to the I&M community.

The Distinguished Lecturers for 2014 are:

- Annamária R. Várkonyi-Kóczy
- Gourab Sen Gupta
- Yong Yan
- Octavian Adrian Postolache
- Robert X. Gao
- Jacob Scharcanski
- Reza Zoughi
- Wuqiang Yan
- Pawel Niewczas

For more information on DLP, visit our [Web site](#) or contact the I&M DLP Chair, [Kristen Donnell](#).

The [Education Committee](#) of the I&M Society provides educational activities for the professional development of the Society membership and for the profession.


For ideas, suggestions, questions, visit our [Web site](#) or email the VP Education and EdCom Chair, [Max Cortner](#).

professional practice for at least ten years and shall have shown significant performance over a period of at least five of those years.

An [application for Senior Membership](#) requires three references unless nominated by a Senior member, and in that case requires two references.

Congratulations to the newly elevated Senior members for 2014 thus far: Robert Estes, Bradley Gulka, Siddharth Ladhake, Horst Rogalla, Grzegorz Wiczynski, Jin Bains, Roberto Tinarelli, William Berger, Teresa Duepner, Pasquale Arpaia, Leonid Belostotski, Jafar Ghaisari, Jian Li, Christopher Salthouse, Yiyu Shi, Jer-Liang Yeh, Bharat Gupta, Paul Haake, Phil Bartley and Manuel C. Blanco.

2014 Awards

 We would like to congratulate Thomas Linnenbrink for his inclusion in the 2014 IEEE Honors Ceremony.

He was awarded the [IEEE Joseph F. Keithley Award in Instrumentation and Measurement](#). His award is credited for his pioneering charge-mode analog-to-digital converters and for developing IEEE-standard converter terminology and test methods.

[View](#) the program for the 2014 IEEE Honors Ceremony.

[Giant Magnetoresistance \(GMR\) Sensors: From Basis to State-of-the-Art Applications](#) (Smart Sensors, Measurement and Instrumentation) , co-authored by S. C. Mukhopadhyay, C. Reig and S. C. de Freitas has been awarded the Distinguished Publication Award from the Magnetics Society of Japan in 2014.

The book is published by Springer-Verlag and was released in 2013.

I&M Administrative Committee

The Instrumentation and Measurement's Society Administrative Committee will meet for their Fall AdCom Meeting 9-11 October 2014 in Stresa, Italy.

The 2014 IEEE Instrumentation and Measurement Society AdCom:

President: Reza Zoughi

Exec. VP: Ruth Dyer

VP Finance: Dario Petri

VP Conf: Alessandra Flammini

VP Pubs: Mark Yeary

VP Membership: Kristen Donnell

VP Technical: Richard C. Hochberg

VP Education: Max Cortner

Treasurer: Frank Reyes

Sr. Past Pres: Kim Fowler

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